



2623

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

10
9-10-03

Application No.: 09/697,025 Confirmation No.: 3437
First Named Inventor: Mehrdad Nikoonahad Filing Date: October 26, 2000
Group Art Unit: 2623 Examiner: Unknown
Atty. Docket No.: TNCR.183US0
Title: OVERLAY ERROR DETECTION
Assignee: KLA-TENCOR CORPORATION

San Francisco, California
March 31st, 2003

COMMISSIONER FOR PATENTS
Washington, D. C. 20231

RECEIVED
APR 10 2003
Technology Center 2600

**SUPPLEMENTAL
INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97, and 1.98, Applicants call the documents listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

☒ Copies of the documents listed on the accompanying Form PTO-1449 are enclosed.

Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a representation that a search has been made (other than as indicated by any cited document), or (3) an admission that the cited information is, or is considered to be, material to patentability as defined in § 1.56(b).

This information disclosure statement is submitted under 37 C.F.R. § 1.97(b) and consequently no fee should be required.

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231, on March 31, 2003.

Valerie Olsen

Valerie Olsen

3/31/03

Date of Signature

Respectfully submitted,

James S. Hsue

Reg. No. 29,545

Attorney for Applicant(s)

U.S. Department of Commerce, Patent and Trademark Office				Atty Docket No.		Application No.	
				TNCR.183US0		09/697,025	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)				Applicant(s)		Confirmation No.	
				Mehrdad Nikoonahad, et al.		3437	
				Filing Date		Group	
				October 26, 2000		2623	

U.S. Patent Documents							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	4,871,955	10/03/89	Berger	318	640	
	AB	5,495,336	02/27/96	Nose et al.	356	375	
	AD						
	AE						
	AF						
	AG						
	AI						
	AJ						
	AD						
	AE						
	AF						
	AG						
	AK						
	AD						
	AE						
	AG						
	AH						
	AI						

Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	AL							
	AM							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)	
AQ	R. Pforr, et al., "In-Process Image Detecting Technique For Determination Of Overlay, And Image Quality For ASM-L Wafer Stepper", <i>SPIE Vol. 1674 Optical/Laser Microlithography V</i> (1992) pp. 594-608

Examiner	Date Considered
----------	-----------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.